National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name : TESSOLVE SEMICONDUCTOR PRIVATE LIMITED, PLOT NO: 31, P2, ELECTRONIC CITY PHASE II, ELECTRONIC CITY., BENGALURU, KARNATAKA, INDIA

Accreditation Standard ISO/IEC 17025:2017

Certificate Number TC-8947 **Page No** 1 of 2

Validity 29/03/2023 to 28/03/2025 **Last Amended on** -

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
Permanent Facility				
1	ELECTRONICS- EMC TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	Charged Device Model (CDM) - Device Level	ANSI/ESDA/JEDEC JS-002
2	ELECTRONICS- EMC TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	Human Body Model (HBM) - Component Level	ANSI-ESDA_-JEDEC_JS-001
3	ELECTRONICS- EMC TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	IC Latch-Up Test	JESD78F
4	ELECTRONICS-ENVIRONMENTAL TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	High Temperature Storage Life	AEC - Q100 - REV-H: Clause - A6 (JESD22-A103E.01: 2021)
5	ELECTRONICS-ENVIRONMENTAL TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	High Temperature Storage Life	JESD22-A103E.01
6	ELECTRONICS-ENVIRONMENTAL TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	Low Temperature Storage Life	JESD22-A119A
7	ELECTRONICS-ENVIRONMENTAL TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	Power and Temperature Cycling	JESD22-A105D
8	ELECTRONICS-ENVIRONMENTAL TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	Temperature cycling	AEC - Q100 - REV-H: Clause-A4 (JESD22-A104F : 2020)
9	ELECTRONICS-ENVIRONMENTAL TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	Temperature cycling	JESD22-A104F
10	ELECTRONICS-ENVIRONMENTAL TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	Temperature, Bias, and Operating Life	JESD22-A108F

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11	ELECTRONICS-ENVIRONMENTAL TEST FACILITY	Electronic components & Equipment sub assemblies such as integrated circuits (ICs) of various packages, semi-conductor devices, Printed Circuit Boards/populated Printed Circuit Boards with components, Transistors etc	Unbiased HAST or Temperature- Humidity (without Bias)	AEC - Q100 - REV-H, Clause-A3 (JESD22-A118B.01: 2021)